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Date: 25 September 2023
Origin: International**Latest date for receipt of comments: 15 November 2023**

Project No. 2023/02100

Responsible committee: EPL/47 Semiconductors

Interested committees:

Title: BS IEC 63512 Test method for continuous-switching evaluation of gallium nitride powerconversion devices

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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

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Please indicate whether you consider the UK should submit a negative (with supporting technical reasons) or positive vote on this draft. Please indicate if you are aware of any reason why this draft standard should not be published as a British Standard.

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



47/2814/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER:

IEC 63512 ED1

DATE OF CIRCULATION:

2023-09-22

CLOSING DATE FOR VOTING:

2023-12-15

SUPERSEDES DOCUMENTS:

IEC TC 47 : SEMICONDUCTOR DEVICES	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Cheolung Cha
OF INTEREST TO THE FOLLOWING COMMITTEES: TC 91, TC 104	PROPOSED HORIZONTAL STANDARD: ☐ Other TC/SCs are requested to indicate their interest, if any, in this CDV to the secretary.
FUNCTIONS CONCERNED: ☐ EMC ☐ ENVIRONMENT ☐ QUALITY ASSURANCE ☐ SAFETY	
☐ SUBMITTED FOR CENELEC PARALLEL VOTING	☒ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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TITLE:

Test method for continuous-switching evaluation of gallium nitride power conversion devices

PROPOSED STABILITY DATE: 2027

NOTE FROM TC/SC OFFICERS:

This CDV is based upon JEDEC document JEP182 (title: TEST METHOD FOR CONTINUOUS-SWITCHING EVALUATION OF GALLIUM NITRIDE POWER CONVERSION DEVICES) and is circulated according to the IEC fast-track procedure (see F.2 of ISO/IEC Directives, Part 1, 2023). This document is proposed by the US National Committee and TC 47/WG8 at the November 2022 meeting approved fast-track procedure as was presented to TC 47 Plenary at the November 2022 Plenary.

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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TEST METHOD FOR CONTINUOUS-SWITCHING EVALUATION OF GALLIUM NITRIDE
POWER CONVERSION DEVICES

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FOREWORD

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The text of this International Standard is based on the following documents:

81

FDIS	Report on voting
XX/XX/FDIS	XX/XX/RVD

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83 Full information on the voting for the approval of this International Standard can be found in the
84 report on voting indicated in the above table.

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